

Notice of References Cited	Application/Control No. 09/910,371		Applicant(s)/Patent Under Reexamination SEEM, JOHN E.	
	Examiner Jeffrey R. West		Art Unit 2857	Page 1 of 1

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*	B	US-2002/0124001	09-2002	Chaudhuri et al.	707/100
*	C	US-6,643,629	11-2003	Ramaswamy et al.	706/45
*	D	US-2001/0004726	06-2001	Lambrecht	702/5
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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*	U	Carey et al., "Resistant and Test-Based Outlier Rejection: Effects on Gaussian One- and Two-Sample Inference". Technometrics, Vol. 39, No. 3. 1999.			
*	V	Sematech, "The Engineers Statistics Internet (ESI) Handbook: Grubbs' Test for Outliers." 1999.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.